

INFORMATION DISCLOSURE CITATION IN AN APPLICATION						ATTY. DOCKET NO. 60188-731		SERIAL NO. 10/736,605			
						APPLICANT Yutaka HIROSE, et al.					
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EXAMINER'S INITIALS		CITE NO.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.								
TJ			HASHIZUME, T., et al. "Characterization of GaN and AlGaIn Surfaces and Their Insulated Gate Structures." The Institute of Electronics, Information and Communication Engineers. Technical Report of IEICE., ED2002-87, LQE2002-62 (2002-08). Pp. 57-60, June 14, 2002.								
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